Argon Chen

List of Publications by Year
in descending order

55	547	567281	677142
papers	**citations**	15	22
		h-index	**g-index**

57	57	57	555
all docs	**docs citations**	**times ranked**	**citing authors**

#	Article	IF	Citations
1	Assessing Detection Accuracy of Computerized Sonographic Features and Computer-Assisted Reading Performance in Differentiating Thyroid Cancers. Biomedicines, 2022, 10, 1513.	3.2	0
2	Multivariate multi-layer classifier. Pattern Recognition, 2022, 131, 108896.	8.1	0
3	Software-Based Analysis of the Taller-Than-Wide Feature of High-Risk Thyroid Nodules. Annals of Surgical Oncology, 2021, 28, 4347-4357.	1.5	4
4	Equipment deterioration modeling and cause diagnosis in semiconductor manufacturing. International Journal of Intelligent Systems, 2021, 36, 2618-2638.	5.7	5
5	ASO Author Reflections: Quantitative Shape Analysis of Thyroid Nodules: A Small But Important Step Towards Software-Based Preoperative Evaluation of Thyroid Nodules. Annals of Surgical Oncology, 2021, 28, 4358-4359.	1.5	0
6	Many-to-many comprehensive relative importance analysis and its applications to analysis of semiconductor electrical testing parameters. Advanced Engineering Informatics, 2021, 48, 101283.	8.0	1
7	Risk Stratification in Patients With Follicular Neoplasm on Cytology: Use of Quantitative Characteristics and Sonographic Patterns. Frontiers in Endocrinology, 2021, 12, 614630.	3.5	4
8	Differences in the ultrasonographic appearance of thyroid nodules after radiofrequency ablation. Clinical Endocrinology, 2021, 95, 489-497.	2.4	3
9	Binary multi-layer classifier. Information Sciences, 2021, 562, 220-239.	6.9	1
10	Ultrasonographic features for differentiating follicular thyroid carcinoma and follicular adenoma. Asian Journal of Surgery, 2020, 43, 339-346.	0.4	40
11	Comprehensive relative importance analysis and its applications to high dimensional gene expression data analysis. Knowledge-Based Systems, 2020, 203, 106120.	7.1	3
12	A2â€PhaseMerge Filter Approach toComputerâ€AidedDetection of Breast Tumors on3â€DimensionalUltrasound Imaging. Journal of Ultrasound in Medicine, 2020, 39, 2439-2455.	1.7	0
13	Multi-Reader Multi-Case Study for Performance Evaluation of High-Risk Thyroid Ultrasound with Computer-Aided Detection. Cancers, 2020, 12, 373.	3.7	11
14	0457 An Effective Mode To Predict Severity Of Obstructive Sleep Apnea: Dynamic Change Of Aerospace Detected By Submental Ultrasonography. Sleep, 2019, 42, A183-A184.	1.1	0
15	A Variance-reduction Approach to Detection of the Thyroid-nodule Boundary on Ultrasound Images. Ultrasonic Imaging, 2019, 41, 206-230.	2.6	4
16	Classification Tree with Hybrid Splitting Mechanism. , 2019, , .		1
17	Computerized Cytological Features for Papillary Thyroid Cancer Diagnosisâ€"Preliminary Report. Cancers, 2019, 11, 1645.	3.7	3
18	Equipment Deterioration Modeling and Causes Diagnosis in Semiconductor Manufacturing. , 2018, , .		0

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19	Can Thyroid Ultrasonography with Computer System Predict Thyroid Follicular Cancer?. Ultrasound in Medicine and Biology, 2017, 43, S113.	1.5	0
20	Quantitative analysis of echogenicity for patients with thyroid nodules. Scientific Reports, 2016, 6, 35632.	3.3	33
21	Efficient Splitting Simulation for Blackout Analysis. IEEE Transactions on Power Systems, 2015, 30, 1775-1783.	6.5	24
22	A variance-reduction method for thyroid nodule boundary detection on ultrasound images. , 2014, , .		2
23	Computerized Quantification of Ultrasonic Heterogeneity in Thyroid Nodules. Ultrasound in Medicine and Biology, 2014, 40, 2581-2589.	1.5	23
24	Quantitative Analysis of Dynamic Power Doppler Sonograms for Patients with Thyroid Nodules. Ultrasound in Medicine and Biology, 2013, 39, 1543-1551.	1.5	23
25	Efficient simulation budget allocation with regression. IIE Transactions, 2013, 45, 291-308.	2.1	26
26	Dominance index for many-to-many correlation and its applicaions to semiconductor yield analysis. , 2012, , .		0
27	Piecewise regression model construction with sample efficient regression tree (SERT) and applications to semiconductor yield analysis. Journal of Process Control, 2012, 22, 1307-1317.	3.3	11
28	Test of covariance changes without a large sample and its application to fault detection and classification. Journal of Process Control, 2012, 22, 1113-1121.	3.3	5
29	Spatial Variance Spectrum Analysis and Its Application to Unsupervised Detection of Systematic Wafer Spatial Variations. IEEE Transactions on Automation Science and Engineering, 2011, 8, 56-66.	5.2	10
30	Rare-event splitting simulation for analysis of power system blackouts. , 2011, , .		15
31	Computerized Detection and Quantification of Microcalcifications in Thyroid Nodules. Ultrasound in Medicine and Biology, 2011, 37, 870-878.	1.5	22
32	Performance analysis of demand planning approaches for aggregating, forecasting and disaggregating interrelated demands. International Journal of Production Economics, 2010, 128, 586-602.	8.9	31
33	Sample-Efficient Regression Trees (SERT) for Semiconductor Yield Loss Analysis. IEEE Transactions on Semiconductor Manufacturing, 2010, 23, 358-369.	1.7	16
34	Analysis of microarray data with multiple phenotypes. , 2009, , .		0
35	Recipe-Independent Indicator for Tool Health Diagnosis and Predictive Maintenance. IEEE Transactions on Semiconductor Manufacturing, 2009, 22, 522-535.	1.7	32
36	Priority Cycle Time Behavior Modeling for Semiconductor Fabs. , 2009, , .		0

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37	Optimum sampling for track PEB CD Integrated Metrology. , 2009, , .		1
38	Weighted least-square estimation of demand product mix and its applications to semiconductor demand. International Journal of Production Research, 2008, 46, 4445-4462.	7.5	7
39	Optimal sampling in design of experiment for simulation-based stochastic optimization. , 2008, , .		1
40	Design of EWMA and CUSUM control charts subject to random shift sizes and quality impacts. IIE Transactions, 2007, 39, 1127-1141.	2.1	42
41	Real-time health prognosis and dynamic preventive maintenance policy for equipment under aging Markovian deterioration. International Journal of Production Research, 2007, 45, 3351-3379.	7.5	59
42	Demand planning approaches to aggregating and forecasting interrelated demands for safety stock and backup capacity planning. International Journal of Production Research, 2007, 45, 2269-2294.	7.5	16
43	Optimal supply chain configurations in semiconductor manufacturing. International Journal of Production Research, 2007, 45, 631-651.	7.5	19
44	Recipe-independent Tool Health Indicator and Fault Prognosis. Semiconductor Manufacturing, Proceedings of the IEEE International Symposium on, 2006, , .	0.0	2
45	Priority Behavior Modeling of Fab for Supply Chain Management. Semiconductor Manufacturing, Proceedings of the IEEE International Symposium on, 2006, , .	0.0	0
46	Sample Efficient Regression Trees (SERT) for Yield Loss Analysis. Semiconductor Manufacturing, Proceedings of the IEEE International Symposium on, 2006, , .	0.0	2
47	Design and Performance Analysis of the Exponentially Weighted Moving Average Mean Estimate for Processes Subject to Random Step Changes. Technometrics, 2002, 44, 379-389.	1.9	17
48	An alternative mean estimator for processes monitored by SPC charts. International Journal of Production Research, 2000, 38, 3093-3109.	7.5	14
49	A selfâ€tuning runâ€byâ€run process controller for processes subject to random disturbances. Journal of the Chinese Institute of Engineers, Transactions of the Chinese Institute of Engineers,Series A/Chung-kuo Kung Ch'eng Hsuch K'an, 1999, 22, 627-638.	1.1	5
50	AN ALTERNATIVE DYNAMIC PROGRAMMING APPROACH TO ALLOCATING INSPECTION POINTS IN MULTISTAGE PRODUCTION SYSTEMS. Quality Engineering, 1998, 11, 197-205.	1.1	1
51	Run-to-run control of CMP process considering aging effects of pad and disc. , 0, , .		2
52	Function-based cost modeling for wafer manufacturing and its application to strategic management. , 0, , .		0
53	Modeling and optimization of wafer-level spatial uniformity with the use of rational subgrouping. , 0, , .		1
54	Run-to-run control schemes for CMP process subject to deterministic drifts. , 0, , .		4

#	Article	IF	Citations
55	An effective SPC approach to monitoring semiconductor quality data with multiple variation sources. , 0, , .		0